

PCN Issue date: 31.07.2014**Products affected :**

INAP375T

Change description:

Qualification of ASE Kaoshiung as test site for probe test in addition to RoodMicrotec in Nördlingen.

The test system remains unchanged. Both test sites use a LTX Credence D10 for wafer probing.

Reason for change:

Reduction of Cycle Time

Reduction of feedback time to wafer fab after probe test

Build up of backup capacity (dual source strategy)

Impact of change:

There is no impact for the customer by this change

Traceability:

Customer will be informed about first production run as soon as PCN is approved by Inova's customers.

Additional Information:

Correlation measurement and Gage R&R results can be found in the attached pdf document